

788-1444

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HN58V256A Series HN58V257A Series

32768-word × 8-bit Electrically Erasable and Programmable CMOS
ROM

HITACHI

ADE-203-357 A (Z)
Rev. 1.0
Apr. 12, 1996

Description

The Hitachi HN58V256A and HN58V257A are a electrically erasable and programmable EEPROM's organized as 32768-word × 8-bit. Employing advanced MNOS memory technology and CMOS process and circuitry technology. They also have a 64-byte page programming function to make their write operations faster.

Features

- Single 2.7 to 5.5 V supply
- On-chip latches: address, data, \overline{CE} , \overline{OE} , \overline{WE}
- Automatic byte write: 10 ms max
- Automatic page write (64 bytes): 10 ms max
- Fast access time: 120 ns max
- Low power dissipation: active: 20 mW/MHz, (typ)
standby: 110 μ W (max)
- Ready/ \overline{Busy} (only the HN58V267A series)
- \overline{Data} polling and Toggle bit
- Data protection circuit on power on/off
- Conforms to JEDEC byte-wide standard
- Reliable CMOS with MNOS cell technology
- 10^5 erase/write cycles (in page mode)
- 10 years data retention
- Software data protection
- Write protection by \overline{RES} pin (only the HN58V267A series)
- Industrial versions (Temperatur range: -20 to 85°C and -40 to 85°C) are also available.



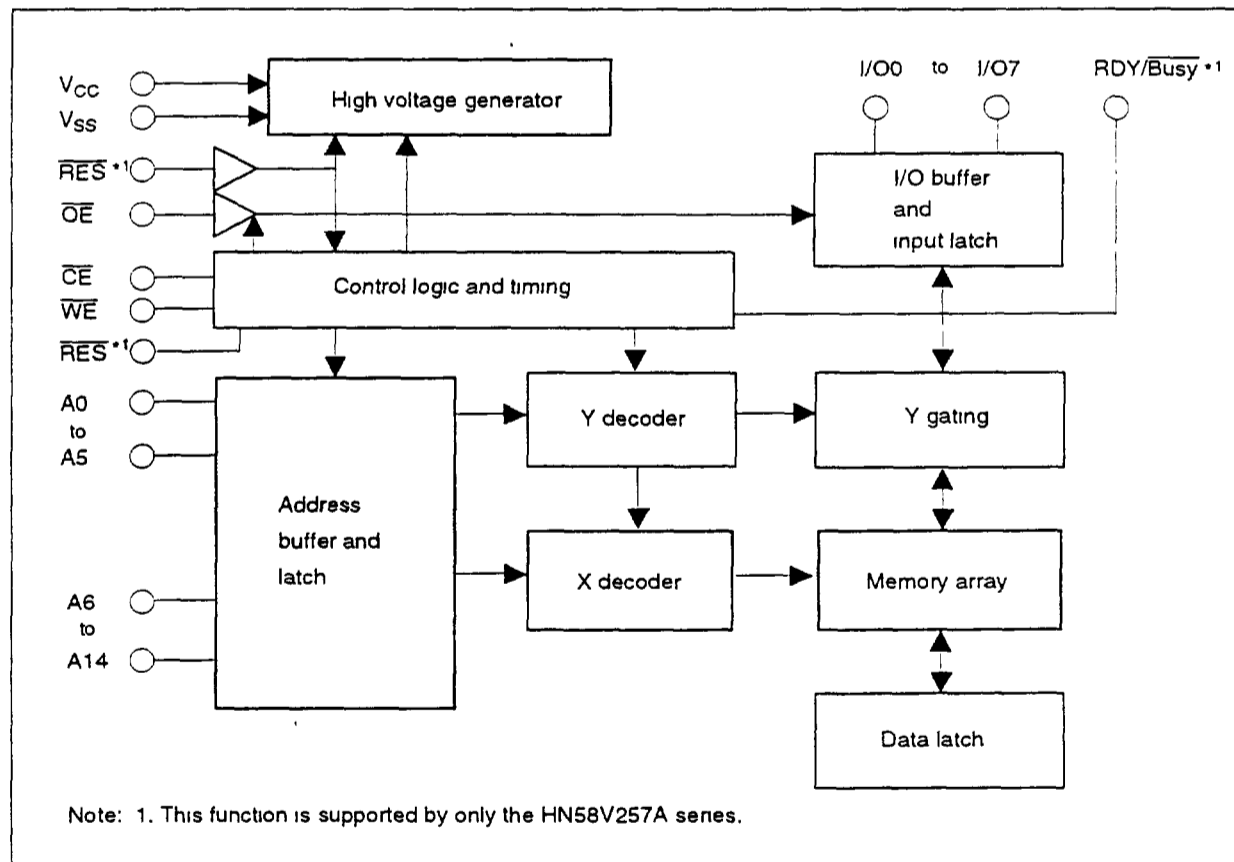
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Pin Description

Pin name	Function
A0 to A14	Address input
I/O0 to I/O7	Data input/output
\overline{OE}	Output enable
\overline{CE}	Chip enable
\overline{WE}	Write enable
V_{CC}	Power supply
V_{SS}	Ground
RDY/Busy*1	Ready busy
\overline{RES}^*	Reset
NC	No connection

Note: 1. This function is supported by only the HN58V257A series.

Block Diagram



HN58V256A Series, HN58V257A Series**Recommended DC Operating Conditions**

Parameter	Symbol	Min	Typ	Max	Unit
Supply voltage	V_{CC}	2.7	3.0	5.5	V
Input voltage	V_{IL}	-0.3 ¹	—	0.6	V
	V_{IH}	1.9 ²	—	$V_{CC} + 0.3$ ³	V
	V_H ⁴	$V_{CC} - 0.5$	—	$V_{CC} + 1.0$	V
Operating temperature	T_{opr}	0	—	70	°C

Notes: 1. V_{IL} min: -1.0 V for pulse width \leq 50 ns.
 2. V_{IH} min for $V_{CC} = 3.6$ to 5.5 V is 2.4 V.
 3. V_{IH} max: $V_{CC} + 1.0$ V for pulse width \leq 50 ns.
 4. This function is supported by only the HN58V257A series.

DC Characteristics ($T_a = 0$ to $+70^\circ\text{C}$, $V_{CC} = 2.7$ to 5.5 V)

Parameter	Symbol	Min	Typ	Max	Unit	Test conditions
Input leakage current	I_{LI}	—	—	2 ¹	μA	$V_{CC} = 5.5$ V, $V_{in} = 5.5$ V
Output leakage current	I_{LO}	—	—	2	μA	$V_{CC} = 5.5$ V, $V_{out} = 5.5/0.4$ V
V_{CC} current (standby)	I_{CC1}	—	—	20	μA	$\overline{CE} = V_{CC}$
	I_{CC2}	—	—	1	mA	$\overline{CE} = V_{IH}$
V_{CC} current (active)	I_{CC3}	—	—	8	mA	$I_{out} = 0$ mA, Duty = 100%, Cycle = 1 μs at $V_{CC} = 3.6$ V
	—	—	—	12	mA	$I_{out} = 0$ mA, Duty = 100%, Cycle = 1 μs at $V_{CC} = 5.5$ V
	—	—	—	12	mA	$I_{out} = 0$ mA, Duty = 100%, Cycle = 120 ns at $V_{CC} = 3.6$ V
	—	—	—	30	mA	$I_{out} = 0$ mA, Duty = 100%, Cycle = 120 ns at $V_{CC} = 5.5$ V
Output low voltage	V_{OL}	—	—	0.4	V	$I_{OL} = 2.1$ mA
Output high voltage	V_{OH}	$V_{CC} \times 0.8$	—	—	V	$I_{OH} = -400$ μA

Note: 1. I_{LI} on $\overline{RES} = 100$ μA max (only the HN58V257A series)

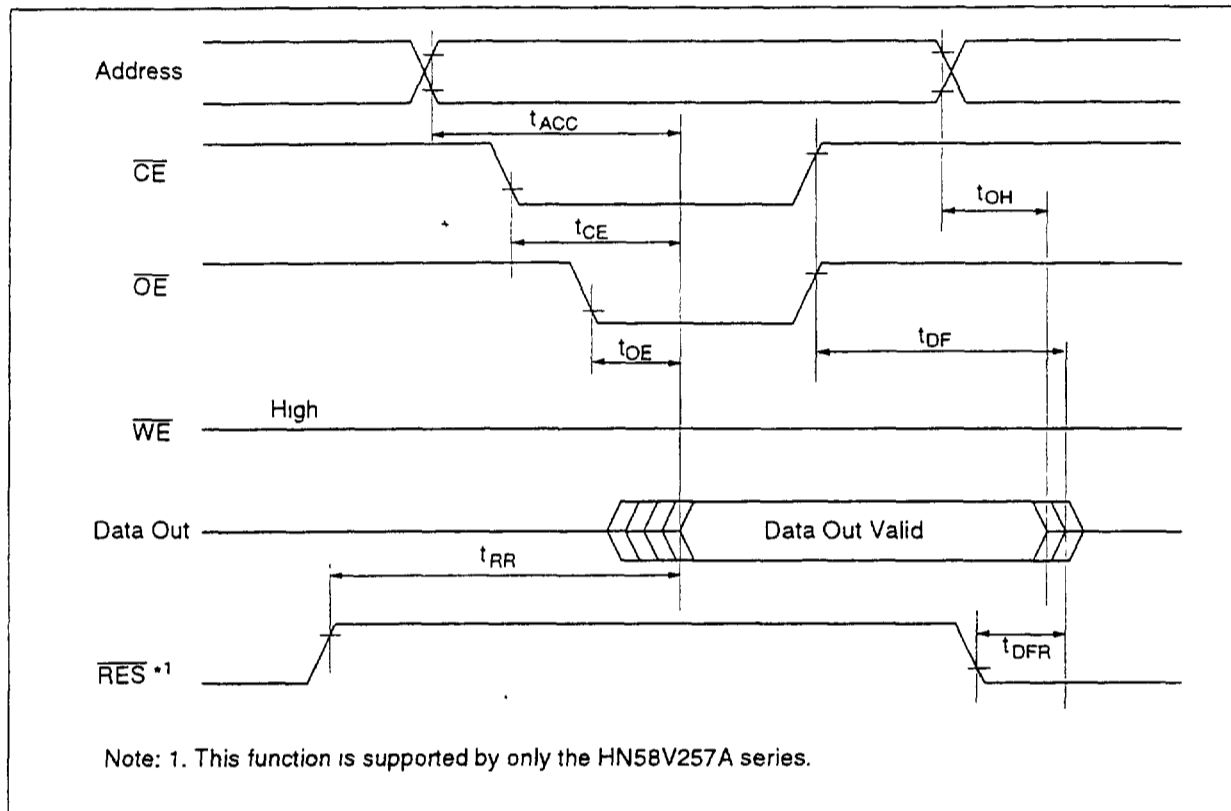
Capacitance ($T_a = 25^\circ\text{C}$, $f = 1$ MHz)

Parameter	Symbol	Min	Typ	Max	Unit	Test conditions
Input capacitance ^{*1}	C_{in}	—	—	6	pF	$V_{in} = 0$ V
Output capacitance ^{*1}	C_{out}	—	—	12	pF	$V_{out} = 0$ V

Note: 1. This parameter is periodically sampled and not 100% tested.

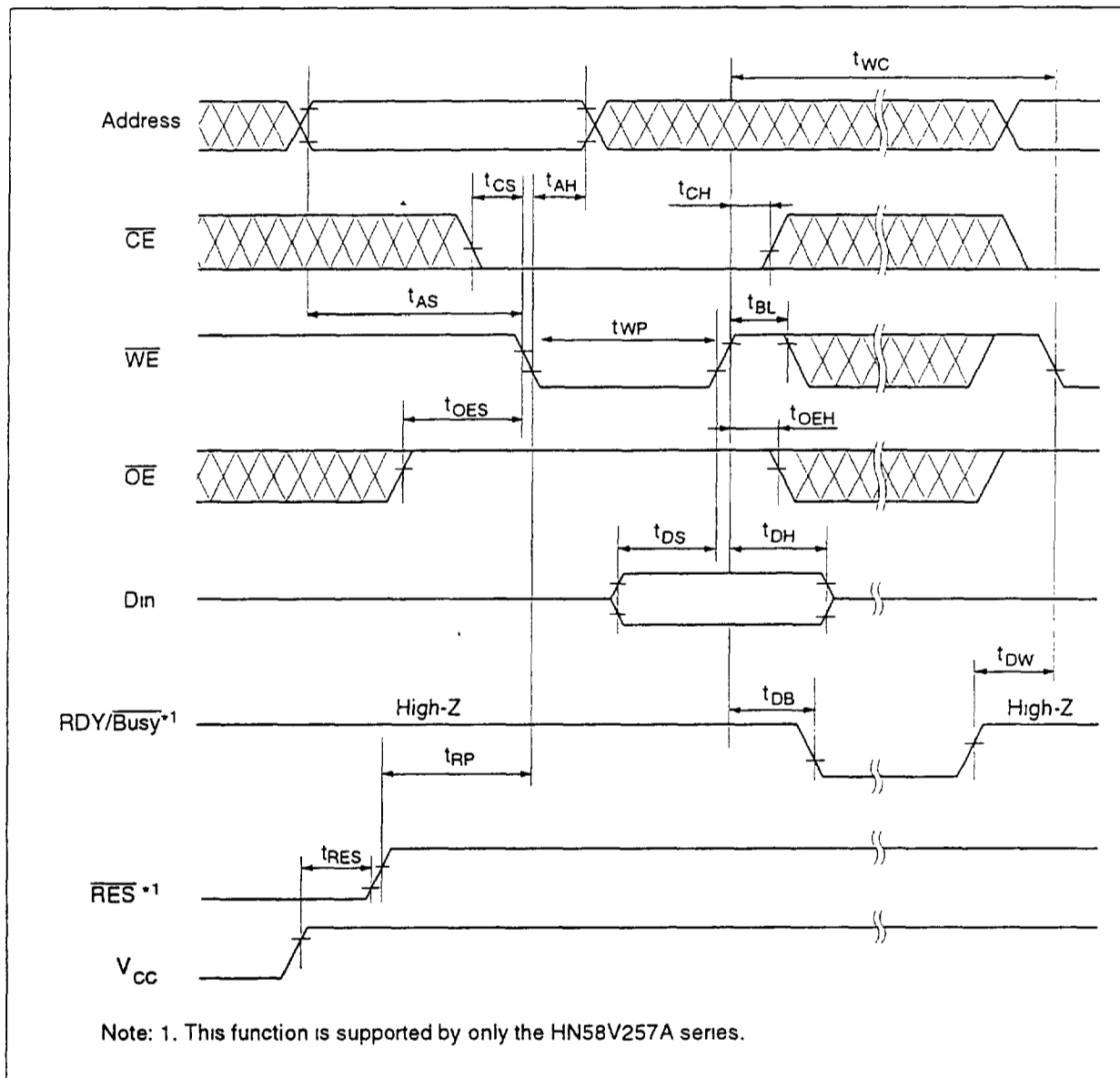
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Read Timing Waveform



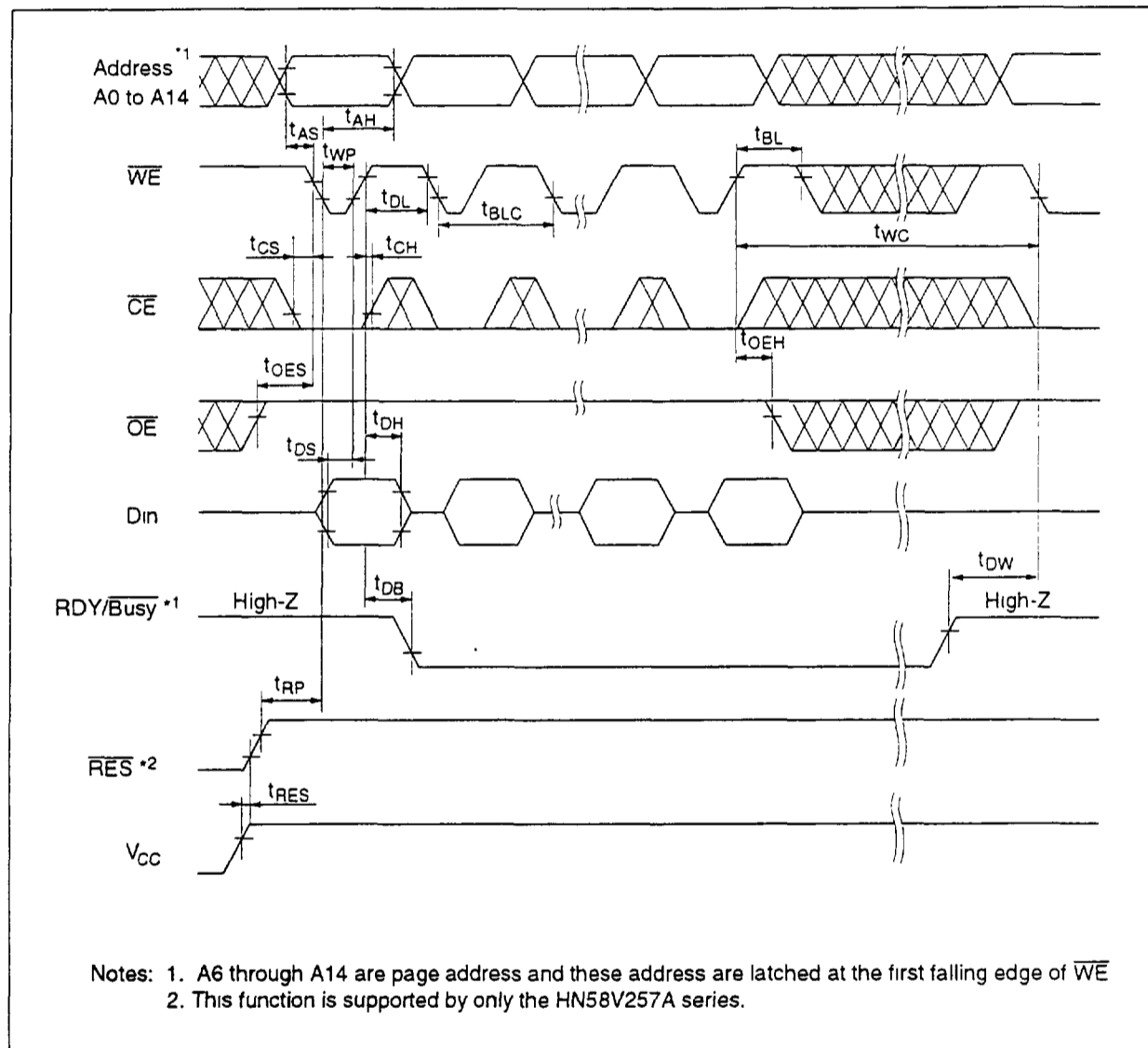
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Byte Write Timing Waveform (1) (\overline{WE} Controlled)



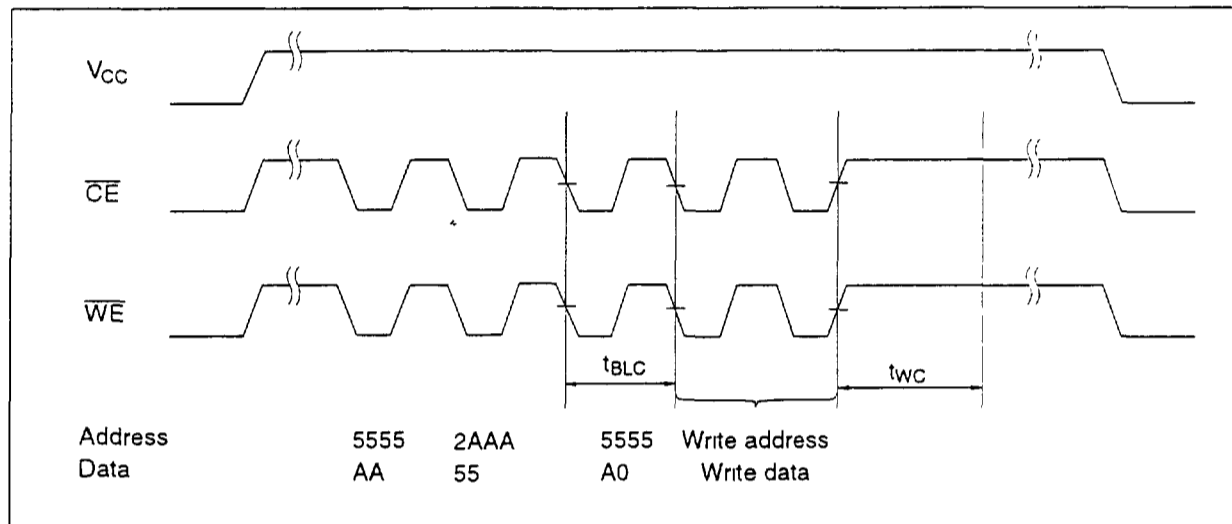
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Page Write Timing Waveform (1) (\overline{WE} Controlled)

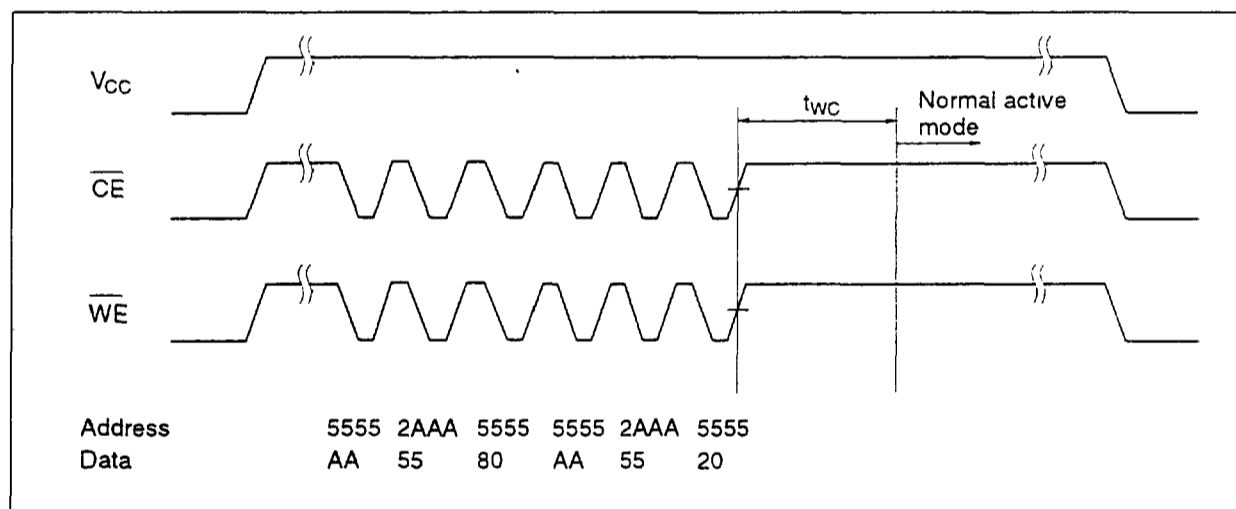


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Software Data Protection Timing Waveform (1) (in protection mode)



Software Data Protection Timing Waveform (2) (in non-protection mode)



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\overline{WE} , \overline{CE} Pin Operation

During a write cycle, addresses are latched by the falling edge of \overline{WE} or \overline{CE} , and data is latched by the rising edge of \overline{WE} or \overline{CE} .

Write/Erase Endurance and Data Retention Time

The endurance is 10^5 cycles in case of the page programming and 10^4 cycles in case of the byte programming (1% cumulative failure rate). The data retention time is more than 10 years when a device is page-programmed less than 10^4 cycles.

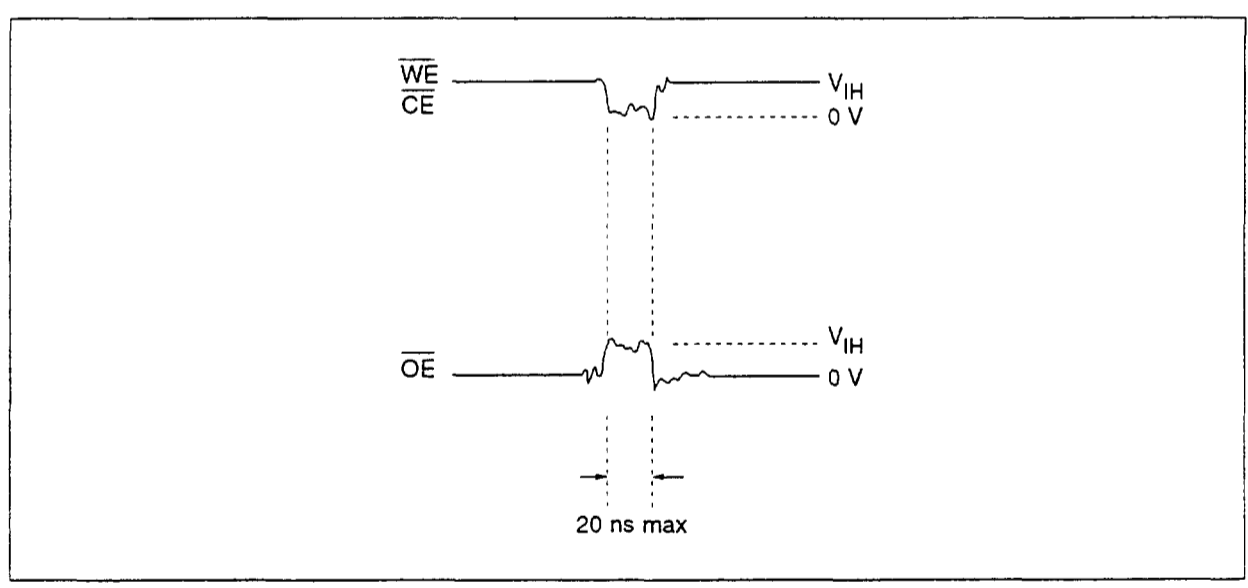
Data Protection

1. Data Protection against Noise on Control Pins (\overline{CE} , \overline{OE} , \overline{WE}) during Operation

During readout or standby, noise on the control pins may act as a trigger and turn the EEPROM to programming mode by mistake.

To prevent this phenomenon, this device has a noise cancelation function that cuts noise if its width is 20 ns or less in program mode.

Be careful not to allow noise of a width of more than 20 ns on the control pins.

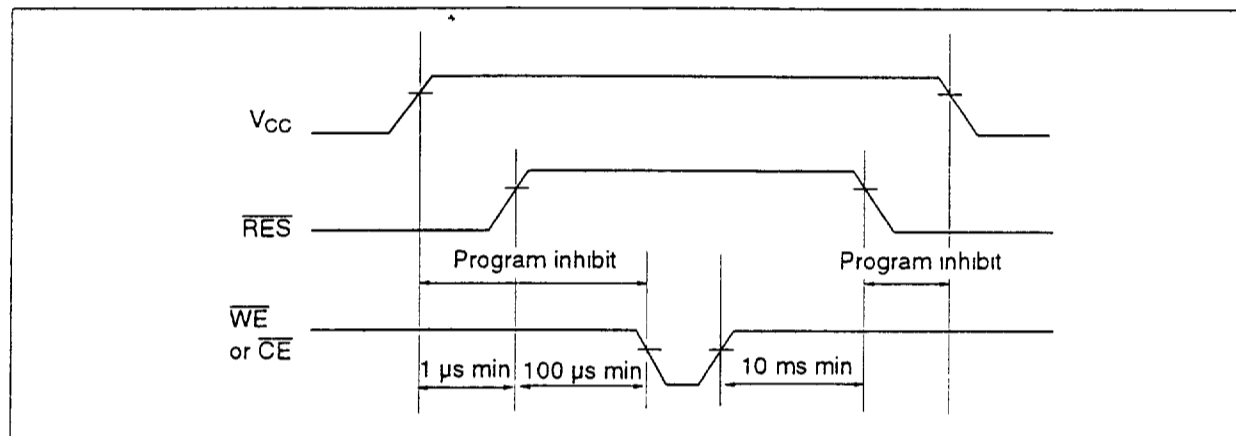


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(2) Protection by $\overline{\text{RES}}$ (only the HN58V257A series)

The unprogrammable state can be realized by that the CPU's reset signal inputs directly to the EEPROM's $\overline{\text{RES}}$ pin. $\overline{\text{RES}}$ should be kept V_{SS} level during V_{CC} on/off.

The EEPROM breaks off programming operation when $\overline{\text{RES}}$ becomes low, programming operation doesn't finish correctly in case that $\overline{\text{RES}}$ falls low during programming operation. $\overline{\text{RES}}$ should be kept high for 10 ms after the last data input.

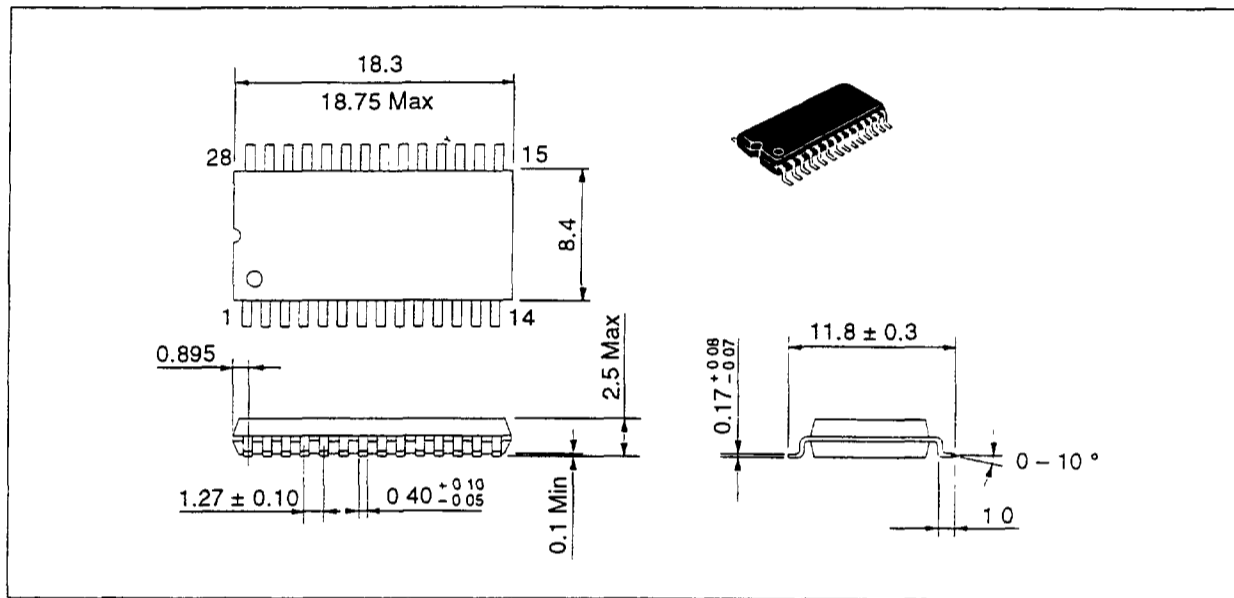


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Package Dimensions

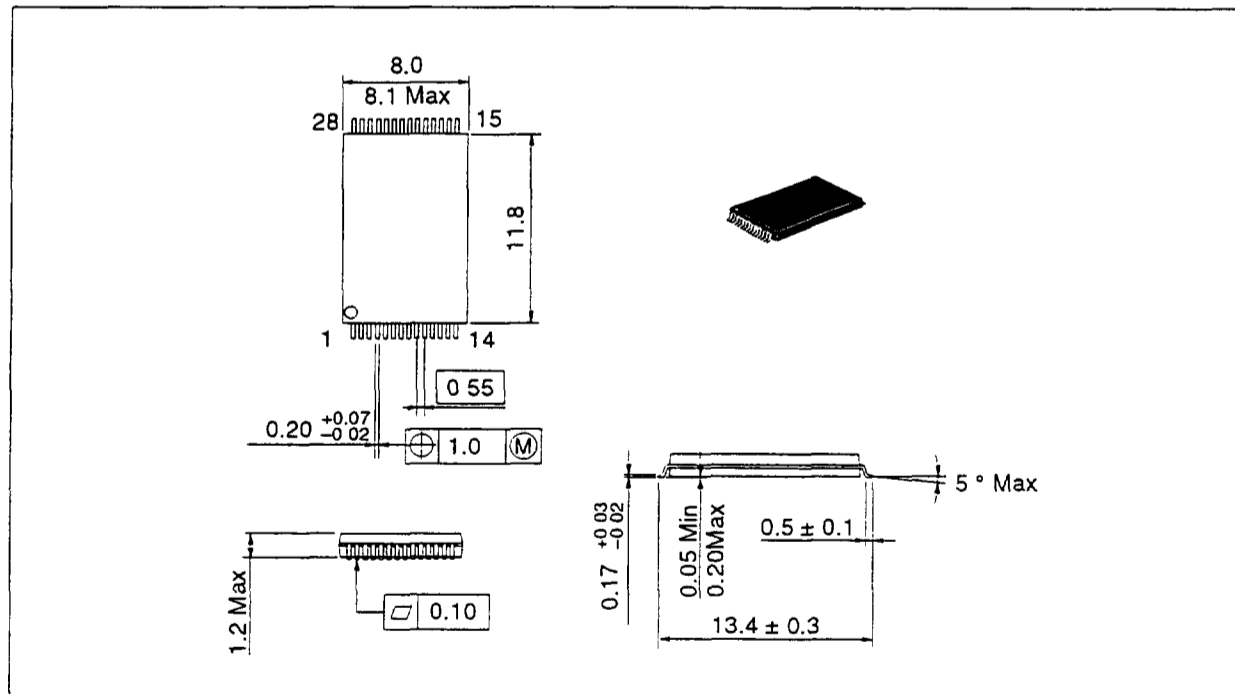
HN58V256AFP Series (FP-28D)

Unit: mm



HN58V256AT Series (TFP-28DB)

Unit: mm



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HITACHI

Hitachi, Ltd.
Semiconductor & IC Div
Nippon Bldg., 2-6-2, Ohte-machi, Chiyoda-ku, Tokyo 100, Japan
Tel: Tokyo (03) 3270-2111
Fax: (03) 3270-5109

For further information write to:

Hitachi America, Ltd.
Semiconductor & IC Div.
2000 Sierra Point Parkway
Brisbane, CA. 94005-1835
U S A
Tel: 415-589-8300
Fax: 415-583-4207

Hitachi Europe GmbH
Electronic Components Group
Continental Europe
Dornacher Straße 3
D-85622 Feldkirchen
München
Tel: 089-9 91 80-0
Fax: 089-9 29 30 00

Hitachi Europe Ltd.
Electronic Components Div
Northern Europe Headquarters
Whitebrook Park
Lower Cookham Road
Maidenhead
Berkshire SL6 8YA
United Kingdom
Tel: 0628-585000
Fax: 0628-778322

Hitachi Asia Pte Ltd
16 Collyer Quay #20-00
Hitachi Tower
Singapore 0104
Tel: 535-2100
Fax: 535-1533

Hitachi Asia (Hong Kong) Ltd
Unit 706, North Tower,
World Finance Centre,
Harbour City, Canton Road
Tsim Sha Tsui, Kowloon
Hong Kong
Tel: 27359218
Fax: 27306071

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